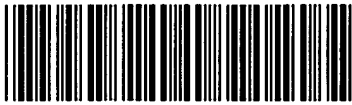


Search Notes

Application/Control No.

10/766,725

Examiner

Chuck Huynh

Applicant(s)/Patent under
Reexamination

CHOI ET AL.

Art Unit

2617

SEARCHED

Class	Subclass	Date	Examiner
Updated	Search	3/29/2006	CH
455	411	3/29/2006	CH

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Look over references	3/29/2006	CH